- 2:00 F03 QUANTITATIVE ANALYSIS BY X-RAY INDUCED TOTAL ELECTRON YIELD (TEY) COMPARED TO XRFA – Invited H. Ebel, Institut für Festkörperphysik, Vienna University of Technology, Vienna, Austria
- 2:30 CONSIDERATIONS FOR OPTIMIZING PRECISION AND ACCURACY OF MULTILAYER THIN FILM MEASUREMENTS – Invited A. Wittkopp, Thermo Noran, Middleton, WI
- 3:00 F05 STANDARDLESS FP ANALYSIS OF THIN FILMS AND MULTIPLE LAYER COATINGS W.T. Elam, R.B. Shen, B. Scruggs, J. Nicolosi, EDAX, Inc., Mahwah, NJ
- 3:20 BREAK
- 3:50 F25 IMPROVEMENTS IN XRF SPECIMEN PREPARATION USING THE DRIED RESIDUE METHOD: GALLIUM IN PLUTONIUM C.G. Worley, Los Alamos National Laboratory, Los Alamos, NM
- 4:10 F37 HALF ABSORBTION PEAK A SPECTRAL ARTIFACT D. Kenning, KeyMaster Technologies, Kennewick, WA

FRIDAY MORNING (A.M.) SPECIAL SESSIONS

C-4 Cement Analysis

Organized by: R. Yellepeddi, Thermo ARL, Ecublens, Switzerland

- 8:30 PROCESS AND QUALITY CONTROL IN THE CEMENT INDUSTRY USING X-RAY INSTRUMENTS: CHALLENGES AND SOLUTIONS – Invited J. Hook, Lehigh Cement Company, Union Bridge, MD
- 9:00 D089 ADVANCES IN QUANTITATIVE XRD ANALYSIS FOR CLINKER, CEMENT (CEM I, CEM II, CEM III) AND CEMENTITIOUS ADDITIONS Invited
 G. Walenta, Lafarge Central Research Laboratories, France
 T. Füllmann, Swiss Federal Institute of Technology, Lausanne, Switzerland
- 9:30 F48 NON-ROUTINE ANALYSIS IN CEMENT INDUSTRY: ENVIRONMENTAL CONTROL, ALTERNATIVE FUELS AND OTHER CENTRAL LAB APPLICATIONS USING STANDARD-LESS ANALYSIS PROGRAMS – Invited A. Buman, R. Yellepeddi, Thermo ARL, Dearborn, MI
- 10:00 BREAK
- 10:20 D049 DEVELOPING AN ASTM STANDARD TEST FOR QUANTITATIVE X-RAY POWDER DIFFRACTION ANALYSIS OF PORTLAND CEMENTS AND CLINKER
 P. Stutzman, National Institute of Standards & Technology
- 10:40 D050 THE USE OF XRD PATTERNS TO EVALUATE THE COMPRESSIVE STRENGTH OF STABILIZED AGGREGATES
 N.N. Khoury, M. Zaman, J.G. Laguros, University of Oklahoma, Norman, OK